Application Note

Analysis of Trace Elements in Water using Ultra Thin Film (1)



When analyzing water solution using the EDX, the detectable and quantifiable concentration range was in the ppm or higher level for the conventional solution measuring method and the spotting filter paper method, where the sample was spotted and dried on filter paper. By replacing the filter paper with ultra thin polymer film, however, quantum improvements have been made to the S/N ratio, enabling detection and quantification to the ppb level. The following introduces the pretreatment and the qualitative results and lower detection limits for trace elements in a sample.

Ultra Thin Polymer Film

A 0.15 μ m polyimide film is stretched in midair across sample holders. A 2 mm diameter section in the center of the film is specially prepared to gather the precipitate after the sample has been dried (see Figs. 1 and 2).

Sample Preparation

Fifty μ L of sample solution was dropped using a micro pipette, and was dried at 70 °C for 40 minutes in a drier (see Fig. 2). Fig. 3 shows the image of the dried sample observed using the optional CCD camera.

Sample

NIST 1643d Trace Elements in Water Table 1 shows the standard values.

Qualitative Analysis

Fig. 4 shows the qualitative analysis results for NIST 1643d. The upper graph shows the result obtained without the filter, while the lower graphs show the results obtained using a Ti filter and a Ni filter, respectively.

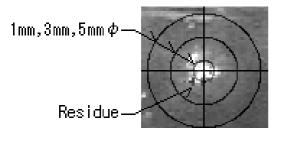
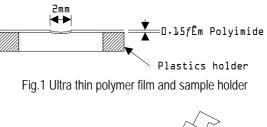
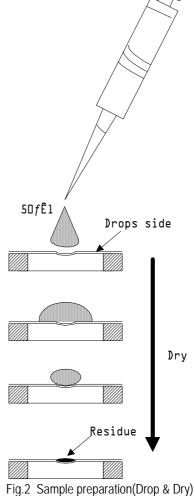


Fig.3 Picture of sample after dry







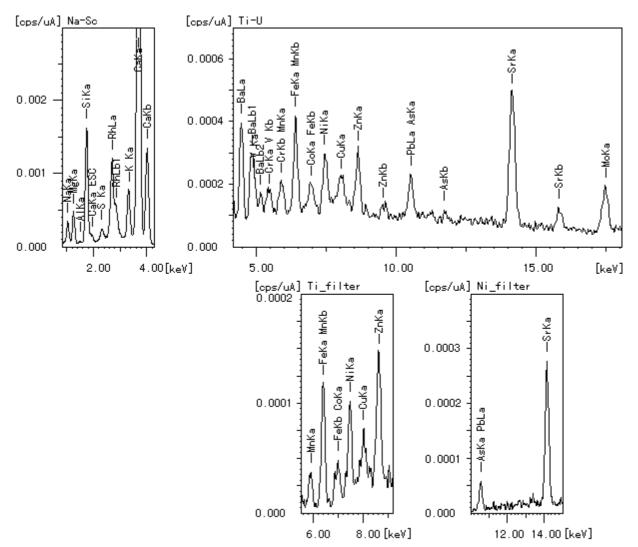


Fig. 4 Qualitative Analysis of NIST1643d

Table 1: Certified or reference Mass Concentrations for
1643d ug/L (ppb) and LLD

1643d µg/L (ppb) and LLD		
Na	22.07 *	1911ppb
Mg	7.989*	406
AI	127.6	
Si	2.7*	44
K	2.365*	121
Ca	31.04*	
V	35.1	
Cr	18.53	
Mn	37.66	12
Fe	91.2	10
Co	25.00	18
Ni	58.1	15
Cu	20.5	
Zn	72.48	15
As	56.02	15
Sr	294.8	18
Мо	112.9	22
Ва	506.5	65
Pb	18.15	
*marked ·mg/l (nnm)Not calculated		

*marked :mg/L(ppm), --Not calculated

Lower Limits of Detection(L.L.D)

Table 1 shows the lower limits of detection calculated from the intensities of the detected elements. The calculation formula is as follows:

 $L.L.D = 3 \times (BG/T)^{1/2} \times C/NET$

where BG: background,

NET: net intensity (cps),

T: measurement time (sec),

C: reference value (ppm/ppb).

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Instrument:	EDX-700
X-ray Tube:	Rh target
Filter:	without Ti, Ni
Voltage - Current:	50kV-(Auto)
	15kV-(Auto)
Atmosphere:	Air,Vacuum
Measurement Diameter:	3 mm
Measurement Time:	1000 sec
Dead Time:	0-12 %



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